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Surface chemical analysis — X-ray photoelectron spectroscopy — Procedures for assessing the day-to-day performance of an X-ray photoelectron spectrometer

*Analyse chimique des surfaces — Spectroscopie de photoélectrons
X — Modes opératoires d'évaluation de la performance au jour le jour
d'un spectromètre de photoélectrons X*



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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Terms and definitions	1
3 Initial approach	1
4 Initial instrument calibration, alignment and assessment	1
5 Test specimen selection	2
5.1 General information	2
5.2 The conductive specimen	2
5.3 The non-conductive specimen	2
5.4 Specimen for assessing the X-ray source	4
6 Collection of reference data	4
6.1 General information	4
6.2 Rapid test of the instrument using a conductive specimen	4
6.3 Rapid test of the instrument using a non-conductive specimen	8
6.4 Rapid test of the X-ray source using a phosphor specimen	8
6.5 Rapid test of the X-ray source using a uniform conductive specimen	8
7 Collection of subsequent performance data	9
8 Analysis of the performance data	9
8.1 General information	9
8.2 Survey spectrum	9
8.3 High-resolution spectrum from the conductive specimen	10
8.4 High-resolution spectrum from the non-conductive specimen	10
8.5 Images from the phosphor specimen	10
8.6 Images from the uniform conductive specimen	10
8.7 Spectrum ratios	10
9 Control charts	15
Bibliography	18

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

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The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

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Introduction

XPS instruments are complex, and unsatisfactory performance is not always obvious to an operator. It is therefore necessary to provide a test for the correct operation of the system that can be performed regularly and frequently without interfering excessively with the normal work of the laboratory.

A full diagnostic test can require many hours or even days; such a test can be appropriate only when the instrument is known to have a fault that needs to be remedied or following a major maintenance procedure. Data acquired before a problem is uncovered become suspect if the spectrometer has not been routinely tested, leading to a loss of confidence in those data. If a regular check of the instrument is made, changes in performance can be monitored and corrective action taken in good time to ensure that the data supplied are fit-for-purpose. In the event that a serious fault is uncovered, then only the data since the last check can be in doubt and need to be repeated.

The purpose of this document is to provide a user with a procedure which is not excessively time-consuming so that it is capable of being completed on a regular and frequent basis, daily if required. The user will then gain an awareness of the current characteristics of the instrument so that a decision can be made as to whether or not a more complete and time-consuming action is required to return the instrument to a satisfactory level of performance.

This procedure is intended to be applied to an XPS instrument that has been correctly calibrated and aligned in accordance with ISO standards or manufacturer's instructions. It is designed to highlight aspects of the instrument's characteristics that differ significantly from those that were measured immediately following the calibration procedure. The procedure does not show how the instrument can be returned to its original state. Instead, it guides the user to possible areas of concern. The procedure provides data that can be used in control charts, allowing trends to be observed and acted upon before data quality deteriorates to an unacceptable level for the needs of the analyst.